


<b>Search Notes</b>  	<b>Application/Control No.</b>  10522231	<b>Applicant(s)/Patent Under Reexamination</b>  MAYER ET AL.
	<b>Examiner</b>  Ahshik Kim	<b>Art Unit</b>  2876

SEARCHED			
Class	Subclass	Date	Examiner
235	454	7/25/07	AK
	491	7/25/07	AK
	462.41	7/25/07	AK
	462.42	7/25/07	AK
	457	7/25/07	AK
356	71	7/25/07	AK
	73.1	7/25/07	AK

SEARCH NOTES			
Search Notes		Date	Examiner
Updated Search		1/30/08	ak

INTERFERENCE SEARCH			
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